新芯微电子
NewChip
Microelectronics

N2M-1200-0025

Silicon Carbide Power MOSFET

N-Channel Enhancement Mode

Features

- High Blocking Voltage with Low On-Resistance
- High Speed Switching with Low Capacitances
- Easy to Parallel and Simple to Drive
- Avalanche Ruggedness
- Halogen Free, RoHS Compliant

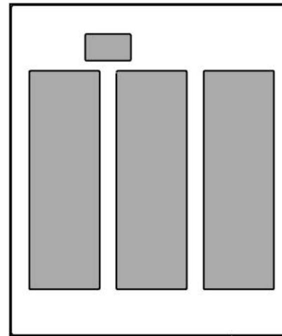
Benefits

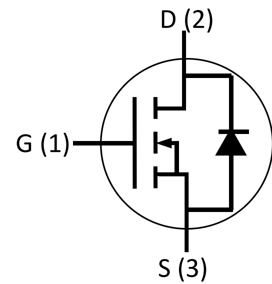
- Higher System Efficiency
- Reduced Cooling Requirements
- Increased Power Density
- Increased System Switching Frequency

Applications

- Solar Inverters
- Switch Mode Power Supplies
- High Voltage DC/DC Converters
- Battery Chargers
- Motor Drives
- Pulsed Power applications

Package





Part Number	Package
N2M-1200-0025	Bare Die

Maximum Ratings (T_c = 25°C unless otherwise specified)

Symbol	Parameter	Value	Unit	Test Conditions	Note
V_{DSmax}	Drain - Source Voltage	1200	V	V_{GS}=0V,I_D=100μA	
V_{GSmax}	Gate - Source Voltage	-10/+25	V	Absolute maximum values	
V_{GSop}	Gate - Source Voltage	-5/+20	V	Recommended operational values	
I_D	Continuous Drain Current	80 45	A	V_{GS}=20V , T_C=25°C V_{GS}=20V , T_C=100°C	
T_J, T_{stg}	Operating Junction and Storage Temperature	-55 to +150	°C		

Electrical Characteristics

Symbol	Parameter	Min.	Typ.	Max.	Unit	Test Conditions	Note
$V_{(BR)DSS}$	Drain-Source Breakdown Voltage	1200			V	V_{GS}=0V, I_D=100μA	
$V_{GS(th)}$	Gate Threshold Voltage	2.0	2.5	4.0	V	V_{GS}= V_{DS}, I_{DS}=15mA, T_C=25°C	Fig. 6
			1.8			V_{GS}= V_{DS}, I_{DS}=15mA, T_C=150°C	
I_{DSS}	Zero Gate Voltage Drain Current		2	100	μA	V_{DS}= 1200V, V_{GS}=0V	
I_{GSS+}	Gate-Source Leakage Current		20	250	nA	V_{GS}=20V, V_{DS}= 0V	
I_{GSS-}	Gate-Source Leakage Current		20	250	nA	V_{GS}=-10V, V_{DS}= 0V	
$R_{DS(on)}$	Drain-Source on-state Resistance		25	38	mΩ	V_{GS}=20V, I_D=50A, T_C=25°C	Fig. 4
			43			V_{GS}=20V, I_D=50A, T_C=150°C	
g_{fs}	Transconductance		14.6		S	V_{GS} = 20 V, I_D = 50A, T_J = 25 °C	Fig. 5
			14.3		S	V_{GS} = 20 V, I_D = 50A, T_J = 150 °C	
Ciss	Input Capacitance		6700		pF	V_{GS}=0V, V_{DS}=1000 V, f=1MHz V_{AC}=25 mV	Fig. 9
Coss	Output Capacitance		188				
Crss	Reverse Transfer Capacitance		42.8				
E_{AS}	Avalanche Energy, Single plus		2.6				
E_{ON}	Turn-On Switching Energy		2.2		mJ	V_{DS}=800V, V_{GS}=-5/20V, I_D= 50 A,	
E_{OFF}	Turn-Off Switching Energy		0.5				
$t_{d(on)}$	Turn-On Delay Time		62		ns	V_{DD}=800V, V_{GS}=-5/20 V I_D = 50A,	
t_r	Rise Time		93				
$t_{d(off)}$	Turn-Off Delay Time		60				
t_f	Fall Time		39				
$R_{G(int)}$	Internal Gate Resistance		0.8		Ω	f=1 MHz, V_{AC}=25mV	
Q_{gs}	Gate to Source Charge		58		nC	V_{DS}=800V, V_{GS}=-5/20 V I_D = 50A	Fig. 10
Q_{gd}	Gate to Drain Charge		90				
Q_g	Total Gate Charge		185				

Reverse Diode Characteristics

Symbol	Parameter	Typ.	Max.	Unit	Test Conditions	Note
V_{SD}	Diode Forward Voltage	3.63		V	V_{GS} = -5V, I_{SD} = 25 A, T_J = 25 °C	Fig. 7
		3.45		V	V_{GS} =- 5V, I_{SD} = 25 A, T_J = 150 °C	Fig. 8
I_S	Continuous Diode Forward Current		90	A	T_C = 25°C	

Mechanical Parameters

Parameter	Typ.	Unit
Die Size	4.77 x 5.61	mm
Souece Pad Size	1.20 x 3.70	mm
Gate Pad Size	0.78 x 0.47	mm
Thickness	180 ± 10%	μm
Wafer Size	150	mm
Top Side Metalization (Al)	4	μm
Bottom Side Metalization (Ni/Ag)	1.5	μm